

ABSTRACT OF THE DISCLOSURE

A wavelength monitoring apparatus according to the present invention constituted by: an optical device made of a periodic multilayer structure; a beam source optically connected to at least one end surface of the multilayer structure, the one end surface being not parallel to layer surfaces of the multilayer structure; and a beam detecting means provided for detecting beam made to exit from at least one surface of the multilayer structure at a specific angle with respect to a specific wavelength, the one surface being parallel to the layer surfaces of the multilayer structure.

(Fig. 6)